

5401/7401 Quadruple 2-Input Positive-NAND Gate with Open-Collector Output

	Schottky TTL					High-Speed TTL					Low-Power Schottky TTL					Standard TTL					Low-Power TTL				
	Device Type	Package				Device Type	Package				Device Type	Package				Device Type	Package				Device Type	Package			
		C	P	M	CF		C	P	M	CF		C	P	M	CF		C	P	M	CF		C	P	M	CF
T.I.						SN54H01	J	③		W2	SN54LS01	J	①		W①	SN5401	J	①		W2	SN54L01				T2
						SN74H01	J	③	N③		SN74LS01	J	①	N①		SN7401	J	①	N①		SN74L01				T2
FAIRCHILD						FM54H01/FM9H01	D	③		F2						FM5401/FM9N01	D	①		F2					
						FC74H01/FC9H01	D	③	P③							FC7401/FC9N01	D	①	P①						
MOTOROLA						MC3104	L	③		F2						MC5401	L	①		F2					
						MC3004	L	③	P③	F③						MC7401	L	①	P①	F2					
N.S.C.						DM54H01	J	③	N③		DM54LS01					DM5401	J	①	N①	W2	DM54L01				F②
						DM74H01	J	③	N③		DM74LS01					DM7401	J	①	N①		DM74L01				F2
PHILIPS																									
						GJH231/74H01			①		N74LS01			①		FJH231/7401			①						
SIGNETICS						S54H01	F	③	A③	W2						S5401	F	①	A①	W2					
						N74H01	F	③	A③		N74LS01			A①		N7401	F	①	A①						
SIEMENS																									
																FLH201			①						
FUJITSU											74LS01			M①		MB416			①	M①					
HITACHI											HD74LS01			P①		HD7401/HD2509			①	P①					
MITSUBISHI																									
																M53201			P①						
NEC																μPB215			D①	C①					
TOSHIBA																TD3401A			P①						

Electrical Characteristics SN54LS01/SN74LS01

absolute maximum ratings over operating free-air temperature range				
Supply voltage, V_{CC}	7V	Operating free-air temperature range	SN54LS	-55°C to 125°C
Input voltage	7V	temperature range	SN74LS	0°C to 100°C
Intermittent voltage	5.5V	Storage temperature range		-65°C to 150°C
recommended operating conditions				
	SN54LS01			UNIT
	MIN	NOM	MAX	
Supply voltage, V_{CC}	4.5	5	5.5	V
High-level output voltage, V_{OH}		5.5	5.5	V
Low-level output current, I_{OL}		4	8	mA
Operating free-air temperature, T_A	-55	125	0	°C

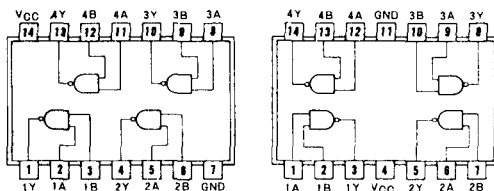
electrical characteristics over recommended operating free-air temperature range

PARAMETER	TEST CONDITIONS †	MIN	TYP ‡	MAX	UNIT
V_{IH} High-level input voltage		2			V
V_{IL} Low-level input voltage			0.8		V
V_I Input clamp voltage	$V_{CC} = \text{MIN.}$, $I_I = -18\text{mA}$		-1.5		V
I_{OH} High-level output current	$V_{CC} = \text{MIN.}$, $V_{IL} = V_{IL \text{ max.}}$, $V_{OH} = 5.5\text{V}$		100		μA
V_{OL} Low-level output voltage	$V_{CC} = \text{MIN.}$, $V_{IH} = 2\text{V}$, $I_{OL} = 4\text{mA}$	0.25	0.4		V
I_I Input current at maximum input voltage	$V_{CC} = \text{MAX.}$, $V_I = 7\text{V}$		0.1		mA
I_{IH} High-level input current	$V_{CC} = \text{MAX.}$, $V_{IH} = 2.7\text{V}$		20		μA
I_{IL} Low-level input current	$V_{CC} = \text{MAX.}$, $V_{IL} = 0.4\text{V}$		0.4		mA
I_{CCH} Supply current	$V_{CC} = \text{MAX.}$	Total, outputs high		4	8
I_{CCL} Supply current	$V_{CC} = \text{MAX.}$	Total, outputs low		12	22
I_{CC} Supply current	$V_{CC} = 5\text{V}$	Average per gate (50% duty cycle)		0.4	mA
t_{PLH} Propagation delay time, low-to-high level output	$V_{CC} = 5\text{V}$, $C_L = 15\text{pF}$, $R_L = 2\text{k}\Omega$	17	32		ns
t_{PHL} Propagation delay time, high-to-low level output	$T_A = 25^\circ\text{C}$	15	28		ns

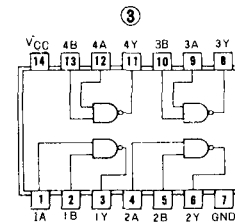
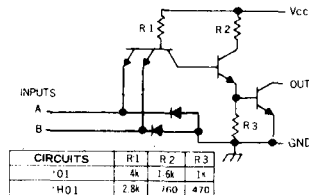
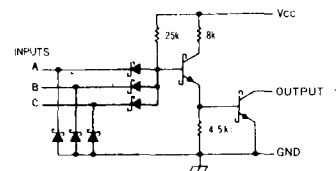
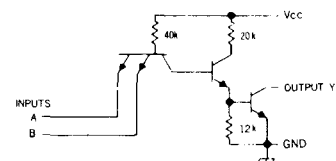
Pin Assignments (Top View)

①

②



positive logic:
Y = AB


Schematics (each gate)

'01, 'H01 CIRCUITS

'LS01 CIRCUIT

'L01 CIRCUIT

Resistor values shown are nominal and in ohms.

†For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
‡All typical values are at $V_{CC} = 5\text{V}$, $T_A = 25^\circ\text{C}$.